

Preface

It is our pleasure to present the proceedings of the 7th Iberian Conference on Pattern Recognition and Image Analysis, IbPRIA 2015. The conference was held in Santiago de Compostela, Spain, following in the footsteps of previous successful meetings in Andraxt (2003), Estoril (2005), Girona (2007), Póvoa de Varzim (2009), Las Palmas de Gran Canaria (2011), and Madeira (2013).

IbPRIA is an international conference co-organized every two years by the Portuguese (APRP - Associação Portuguesa de Reconhecimento de Padrões) and Spanish (AERFAI - Asociación Española de Reconocimiento de Formas y Análisis de Imágenes) chapters of the IAPR International Association for Pattern Recognition. IbPRIA is a single-track conference consisting of high-quality, previously unpublished papers, presented either orally or as a poster, intended to act as a forum for research groups, engineers, and practitioners to present recent results, algorithmic improvements, and promising future directions in pattern recognition and image analysis.

This year's IbPRIA was held during June 17–19, 2015, in Santiago de Compostela, Spain and was hosted by the University of Santiago de Compostela, with the support of CITIUS (Centro Singular de Investigación en Tecnoloxías da Información).

There was a very positive response to the Call for Papers for IbPRIA 2015. We received 141 full papers from 36 countries and 83 were accepted (35 as oral and 48 as poster) for presentation at the conference, where each paper was reviewed by at least two reviewers. The high quality of the scientific program of IbPRIA 2015 was due first to the authors who submitted excellent contributions and second to the dedicated collaboration of the international Program Committee and the other researchers who reviewed the papers. We would like to thank all the authors for submitting their contributions and for sharing their research activities. We are particularly indebted to the Program Committee members and to all the reviewers for their precious evaluations, which permitted us to produce this publication.

We were also very pleased to benefit from the participation of the invited speakers Raquel Urtasun, University of Toronto, Jesús Malo, Universitat de València, and Professor Daniel Cremers, Technical University of Munich. We would like to express our sincere gratitude to these world-renowned experts.

The work of the seven co-chairs was also very valuable. Furthermore, we are also grateful to all members of the local Organizing Committee. Their work was essential to the success of IbPRIA 2015.

Finally, we look forward to meeting you at the next edition of IbPRIA, in Portugal in 2017.

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